SN54F27, SN74F27 TRIPLE 3-INPUT POSITIVE-NOR GATES

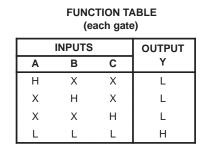
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 Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

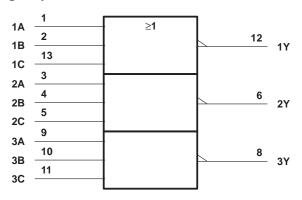
description

These devices contain three independent 3-input NOR gates. They perform the Boolean functions $Y = \overline{A} \bullet \overline{B} \bullet \overline{C}$ or $Y = \overline{A + B + C}$ in positive logic.

The SN54F27 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74F27 is characterized for operation from 0°C to 70°C.

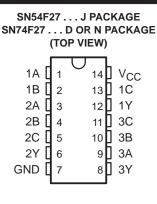


logic symbol[†]

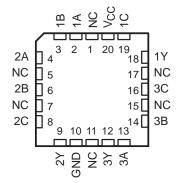


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

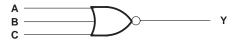


SN54F27 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic diagram, each gate (positive logic)



PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54F27, SN74F27 **TRIPLE 3-INPUT POSITIVE-NOR GATES**

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1)	
Input current range	
Voltage range applied to any output in the high state	
Current into any output in the low state	40 mÅ
Operating free-air temperature range: SN54F27	. −55°C to 125°C
SN74F27	0°C to 70°C
Storage temperature range	. −65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

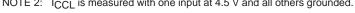
		SN54F27		SN74F27			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
Iк	Input clamp current			-18			-18	mA
ЮН	High-level output current			- 1			- 1	mA
IOL	Low-level output current			20			20	mA
ТА	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	т	EST CONDITIONS		SN54F27			SN74F27		
		EST CONDITIONS	MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = 4.5 V,	l _l = –18 mA			-1.2			-1.2	V
Veri	V _{CC} = 4.5 V,	I _{OH} = – 1 mA	2.5	3.4		2.5	3.4		v
VOH	V _{CC} = 4.75 V,	I _{OH} = – 1 mA				2.7			
VOL	V _{CC} = 4.5 V,	I _{OL} = 20 mA		0.3	0.5		0.3	0.5	V
l	V _{CC} = 5.5 V,	V ₁ = 7 V			0.1			0.1	mA
ЧΗ	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
ΙL	V _{CC} = 5.5 V,	V _I = 0.5 V			- 0.6			- 0.6	mA
IOS§	V _{CC} = 5.5 V,	$V_{O} = 0$	-60		-150	-60		-150	mA
ІССН	V _{CC} = 5.5 V,	$V_{I} = 0$		3.8	5.5		3.8	5.5	mA
ICCL	V _{CC} = 5.5 V,	See Note 2		8.4	12		8.4	12	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. NOTE 2: I_{CCL} is measured with one input at 4.5 V and all others grounded.





SN54F27, SN74F27 TRIPLE 3-INPUT POSITIVE-NOR GATES

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switching characteristics (see Note 3)

		,								
PARAMETER	FROM ER (INPUT)	ТО (ОUТРUТ)	V _{CC} = 5 V, C _L = 50 pF, R _L = 500 Ω, T _A = 25°C		V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500Ω, T _A = MIN to MAX [†]			V,	UNIT	
				′F27		SN54F27		SN74	F27	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	x
^t PLH	A, B, or C	v	1.2	3.1	5	1	6	1	5.5	ns
t _{PHL}			1	2.1	4.5	1	5.5	1	4.5	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



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